

EBU Tech 3325 – TEST PATTERNS



NOTE

The test patterns are delivered in yuv10 format at the moment . The .v210 version will be generated as soon as possible and integrated to the Zip.

The test pattern 6 – for scrolling text will be delivered as soon as possible. You can design a similar test pattern on the basis of the description given in the Tech 3325 document.

ACKNOWLEDGEMENT

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EBU P/Display project group.